

<b>Notice of References Cited</b>	Application/Control No. 10/628,827	Applicant(s)/Patent Under Reexamination HENSON ET AL.	
	Examiner Devona E. Faulk	Art Unit 2615	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,796,851	08-1998	Hewitt et al.	381/94.5
*	B	US-5,764,005	06-1998	Kobayashi, Masaki	315/382
*	C	US-6,783,073	08-2004	Yahagi et al.	235/462.28
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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